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Elektromagnetisk kompatibilitet (EMC) – Del 4-6: Mät- och provningsmetoder – Immunitet mot ledningsbundna störningar orsakade av radiofrekventa fält

*Electromagnetic compatibility (EMC) –
Part 4-6: Testing and measurement techniques –
Immunity to conducted disturbances, induced by radio-frequency fields*

Som svensk standard gäller europastandarden EN 61000-4-6:2009. Den svenska standarden innehåller den officiella engelska språkversionen av EN 61000-4-6:2009.

Nationellt förord

Europastandarden EN 61000-4-6:2009

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SEK Svensk Elstandard

Box 1284
164 29 Kista
Tel 08-444 14 00
www.elstandard.se

EUROPEAN STANDARD
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EN 61000-4-6

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Supersedes EN 61000-4-6:2007 + IS1:2009

English version

**Electromagnetic compatibility (EMC) -
Part 4-6: Testing and measurement techniques -
Immunity to conducted disturbances, induced by radio-frequency fields
(IEC 61000-4-6:2008)**

Compatibilité électromagnétique (CEM) -
Partie 4-6: Techniques d'essai
et de mesure -
Immunité aux perturbations conduites,
induites par les champs radioélectriques
(CEI 61000-4-6:2008)

Elektromagnetische Verträglichkeit (EMV) -
Teil 4-6: Prüf- und Messverfahren -
Störfestigkeit gegen leitungsgeführte
Störgrößen, induziert
durch hochfrequente Felder
(IEC 61000-4-6:2008)

This European Standard was approved by CENELEC on 2009-03-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland and the United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: avenue Marnix 17, B - 1000 Brussels

Foreword

The text of document 77B/571/FDIS, future edition 3 of IEC 61000-4-6, prepared by SC 77B, High frequency phenomena, of IEC TC 77, Electromagnetic compatibility, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61000-4-6 on 2009-03-01.

This European Standard supersedes EN 61000-4-6:2007 + corrigendum August 2007 + IS1:2009.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2009-12-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2012-03-01

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 61000-4-6:2008 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

- | | |
|---------------|------------------------------------------------------|
| IEC 61000-4-3 | NOTE Harmonized as EN 61000-4-3:2006 (not modified). |
| CISPR 16-1-2 | NOTE Harmonized as EN 55016-1-2:2004 (not modified). |
| CISPR 20 | NOTE Harmonized as EN 55020:2007 (not modified). |
-

Annex ZA
(normative)

**Normative references to international publications
with their corresponding European publications**

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-161	¹⁾	International Electrotechnical Vocabulary (IEV) - Chapter 161: Electromagnetic compatibility	-	-

¹⁾ Undated reference.

CONTENTS

INTRODUCTION	7
1 Scope and object	8
2 Normative references	8
3 Terms and definitions	8
4 General	10
5 Test levels	10
6 Test equipment	11
6.1 Test generator	11
6.2 Coupling and decoupling devices	12
6.2.1 Coupling/decoupling networks (CDNs)	12
6.2.2 Clamp injection devices	13
6.2.3 Direct injection devices	14
6.2.4 Decoupling networks	14
6.3 Verification of the common mode impedance at the EUT port of coupling and decoupling devices	14
6.3.1 Insertion loss of the 150 Ω to 50 Ω adapters	15
6.4 Setting of the test generator	15
6.4.1 Setting of the output level at the EUT port of the coupling device	15
7 Test set-up for table-top and floor-standing equipment	16
7.1 Rules for selecting injection methods and test points	16
7.1.1 Injection method	16
7.1.2 Ports to be tested	17
7.2 Procedure for CDN injection application	18
7.3 Procedure for clamp injection when the common-mode impedance requirements can be met	18
7.4 Procedure for clamp injection when the common-mode impedance requirements cannot be met	19
7.5 Procedure for direct injection	19
7.6 EUT comprising a single unit	19
7.7 EUT comprising several units	20
8 Test procedure	20
9 Evaluation of the test results	21
10 Test report	21
Annex A (normative) Additional information regarding clamp injection	33
Annex B (informative) Selection criteria for the frequency range of application	38
Annex C (informative) Guide for selecting test levels	40
Annex D (informative) Information on coupling and decoupling networks	41
Annex E (informative) Information for the test generator specification	45
Annex F (informative) Test set-up for large EUTs	46
Annex G (informative) Measurement uncertainty of test instrumentation	49
Bibliography	56
Figure 1 – Rules for selecting the injection method	17

Figure 2 – Immunity test to RF conducted disturbances	23
Figure 3 – Test generator set-up	24
Figure 4 – Open circuit waveforms at the EUT port of a coupling device for test level 1	24
Figure 5 – Principle of coupling and decoupling	27
Figure 6 – Principle of coupling and decoupling according to the clamp injection method	27
Figure 7 – Details of set-ups and components to verify the essential characteristics of coupling and decoupling devices and the $150\ \Omega$ to $50\ \Omega$ adapters	29
Figure 8 – Set-up for level setting (see 6.4.1)	30
Figure 9 – Example of test set-up with a single unit EUT	31
Figure 10 – Example of a test set-up with a multi-unit EUT	32
Figure A.1 – Circuit for level setting set-up in a $50\ \Omega$ test Jig	34
Figure A.2 – The $50\ \Omega$ test jig construction	34
Figure A.3 – Construction details of the EM clamp	35
Figure A.4 – Concept of the EM clamp (electromagnetic clamp)	36
Figure A.5 – Coupling factor of the EM clamp	36
Figure A.6 – General principle of a test set-up using injection clamps	37
Figure A.7 – Example of the test unit locations on the ground plane when using injection clamps (top view)	37
Figure B.1 – Start frequency as function of cable length and equipment size	39
Figure D.1 – Example of a simplified diagram for the circuit of CDN-S1 used with screened cables (see 6.2.1)	42
Figure D.2 – Example of simplified diagram for the circuit of CDN-M1/-M2/-M3 used with unscreened supply (mains) lines (see 6.2.1.1)	42
Figure D.3 – Example of a simplified diagram for the circuit of CDN-AF2 used with unscreened non-balanced lines (see 6.2.1.3)	43
Figure D.4 – Example of a simplified diagram for the circuit of a CDN-T2, used with an unscreened balanced pair (see 6.2.1.2)	43
Figure D.5 – Example of a simplified diagram of the circuit of a CDN-T4 used with unscreened balanced pairs (see 6.2.1.2)	44
Figure D.6 – Example of a simplified diagram of the circuit of a CDN-T8 used with unscreened balanced pairs (see 6.2.1.2)	44
Figure F.1 – Example of large EUT test set-up with elevated horizontal ground reference plane	47
Figure F.2 – Example of large EUT test set-up with vertical ground reference plane	48
Figure G.1 – Example of influences upon the test method using CDN	49
Figure G.2 – Example of influences upon the test method using EM clamp	50
Figure G.3 – Example of influences upon the test method using current clamp	50
Figure G.4 – Example of influences upon the test method using direct injection	50
Table 1 – Test levels	11
Table 2 – Characteristics of the test generator	12
Table 3 – Main parameter of the combination of the coupling and decoupling device	12
Table B.1 – Main parameter of the combination of the coupling and decoupling device when the frequency range of test is extended above 80 MHz	38
Table E.1 – Required power amplifier output power to obtain a test level of 10 V	45
Table G.1a – CDN calibration process	51

Table G.1b – CDN test process	51
Table G.2a – EM clamp calibration process	53
Table G.2b – EM clamp test process	53
Table G.3a – Current clamp calibration process.....	54
Table G.3b – Current clamp test process.....	54
Table G.4a – Direct injection calibration process	55
Table G.4b – Direct injection test process.....	55

INTRODUCTION

IEC 61000 is published in separate parts according to the following structure:

Part 1: General

General considerations (introduction, fundamental principles)
Definitions, terminology

Part 2: Environment

Description of the environment
Classification of the environment
Compatibility levels

Part 3: Limits

Emission limits
Immunity limits (in so far as they do not fall under the responsibility of the product committees)

Part 4: Testing and measurement techniques

Measurement techniques
Testing techniques

Part 5: Installation and mitigation guidelines

Installation guidelines
Mitigation methods and devices

Part 6: Generic standards

Part 9: Miscellaneous

Each part is further subdivided into several parts, published either as international standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example : 61000-6-1).

This part is an international standard which gives immunity requirements and test procedure related to conducted disturbances induced by radio-frequency fields.

ELECTROMAGNETIC COMPATIBILITY (EMC) –

Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields

1 Scope and object

This part of IEC 61000 relates to the conducted immunity requirements of electrical and electronic equipment to electromagnetic disturbances coming from intended radio-frequency (RF) transmitters in the frequency range 9 kHz up to 80 MHz. Equipment not having at least one conducting cable (such as mains supply, signal line or earth connection) which can couple the equipment to the disturbing RF fields is excluded.

NOTE 1 Test methods are defined in this part for measuring the effect that conducted disturbing signals, induced by electromagnetic radiation, have on the equipment concerned. The simulation and measurement of these conducted disturbances are not adequately exact for the quantitative determination of effects. The test methods defined are structured for the primary objective of establishing adequate repeatability of results at various facilities for quantitative analysis of effects.

The object of this standard is to establish a common reference for evaluating the functional immunity of electrical and electronic equipment when subjected to conducted disturbances induced by radio-frequency fields. The test method documented in this part of IEC 61000 describes a consistent method to assess the immunity of an equipment or system against a defined phenomenon.

NOTE 2 As described in IEC Guide 107, this standard is a basic EMC publication for use by product committees of the IEC. As also stated in Guide 107, the IEC product committees are responsible for determining whether this immunity test standard should be applied or not, and if applied, they are responsible for determining the appropriate test levels and performance criteria. TC 77 and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular immunity tests for their products.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-161, *International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic compatibility*

